Test Benches

Module 8

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Overview

- We have concentrated on VHDL for synthesis
- Can also use VHDL as a test language
- Very important to conduct comprehensive verification on your design
- To simulate your design you need to produce an additional ENTITY and ARCHITECTURE design.
 - Usually referred to as a TEST BENCH
 - Not hardware, just additional VHDL!

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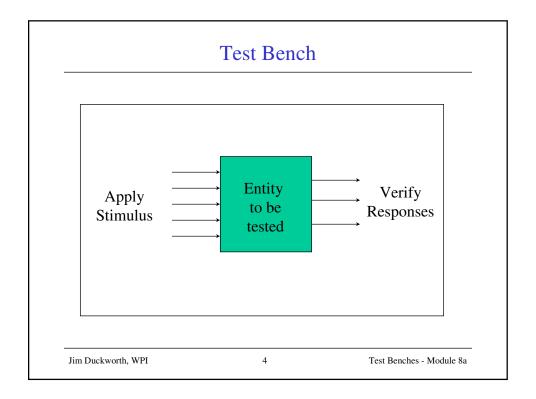
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Test Bench

- A model used to exercise and verify the correctness of a hardware model
- Has three main purposes
 - to generate stimulus for simulation
 - to apply this stimulus to the entity under test and to collect output responses
 - to compare output responses with expected values
- Test Bench should be created by a different engineer than the one who created the synthesizable VHDL

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Test Bench Overview

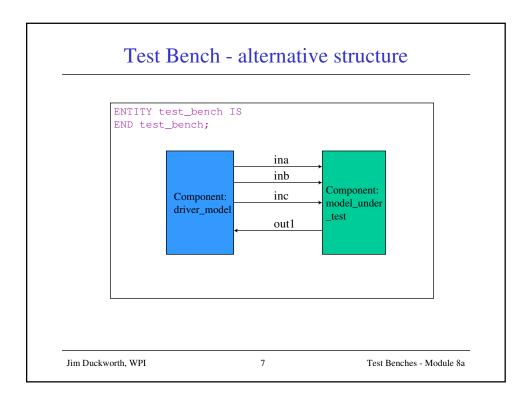
- A Test Bench consists of
 - Entity
 - has no ports (empty entity header)
 - Architecture
 - declares, instantiates, and wires together the driver model and the model under test
 - · driver model provides stimulus and verifies model responses
 - Configuration
 - specify the test case of the driver model and the version of the model under test

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Test Bench - general structure ENTITY test_bench IS END test_bench; ARCHITECTURE tb1 OF test_bench IS test_component declaration internal signal declarations BEGIN UUT: test_component instantiation signals to generate stimulus assert statements to verify repsonses END tb1; ina inb test_component out1 Jim Duckworth, WPI 6 Test Benches - Module 8a



Test Bench - template ENTITY test_bench IS END test_bench; ARCHITECTURE test-fixture OF test_bench IS COMPONENT driver_model END COMPONENT; COMPONENT model_under_test END COMPONENT; SIGNAL -- wires to connect together BEGIN -- component instantiations END test_fixture; Jim Duckworth, WP1 8 Test Benches - Module 8a

VHDL for Test Generation

- We need to look at new VHDL constructs to support our test bench design
- Modeling Time
- Generating Waveforms
- The Assert Statement
- NOTE: The following examples are for testing NOT for synthesis

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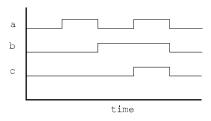
Modeling Time (not for synthesis)

• Example: 2 input AND gate

c <= a AND b;

a ____ & ___ c

• c changes value immediately after a change on the inputs a or b



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Adding Propagation Delays

```
ARCHITECTURE behav OF and_gate_model IS
BEGIN

PROCESS(a, b)
BEGIN

c <= a AND b; -- instantaneous change

-- adding "AFTER" to add delay

c <= a AND b AFTER 10 ns; -- same tphl and tplh

-- If we need different propagation delays:

IF a = '1' AND b = '1' THEN

c <= '1' AFTER 9 ns -- tplh

ELSE

c <= '0' AFTER 10 ns -- tphl

END IF;
```

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Adding Propagation Delays (cont'd)

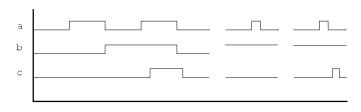
- This is called the <u>Inertial Delay Model</u> (default)
- Models delays of most switching circuits
- If input pulse is shorter than the time expression (switching time of circuit) then no change occurs on the output.

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Transport Delay Model (only for modeling)

- Transport delay is an optional delay model for signal assignment.
- Any pulse is transmitted, no matter how short its duration.



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Generating Arbitrary Waveforms

• It is possible to assign multiple values to a signal

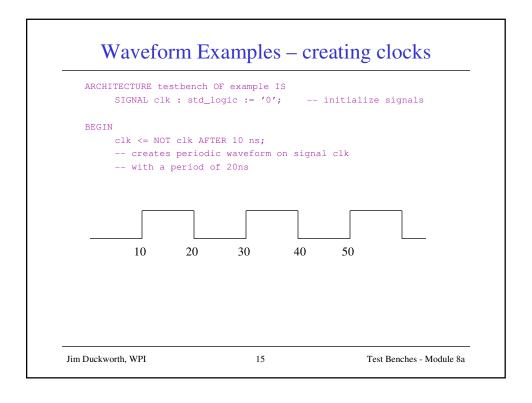
```
a <='0', '1' AFTER 8 ns, '0' AFTER 13 ns, '1' AFTER 50 ns;
```

- When this signal assignment is executed (at time T) it causes four events to be scheduled for signal *a*
 - '0' at T
 - '1' at T + 8
 - '0' at T + 13
 - '1' at T + 50



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Waveform Examples – more clocks PROCESS -- Note: no sensitivity list BEGIN clk <= '0'; WAIT FOR 20 ns; clk <= '1'; WAIT FOR 12 ns; END PROCESS; - OR clk <= '1' AFTER 20 ns WHEN clk = '0' ELSE '0' AFTER 12 ns; 20 32 52 64 84 Jim Duckworth, WPI 16 Test Benches - Module 8a

Waveform Examples – more clocks

• Example of two-phase clock

```
SIGNAL clk1, clk2 : std_logic := '0';
   two_phase: PROCESS
   BEGIN
        clk1 <= '0', '1' AFTER 5 ns, '0' AFTER 20 ns;
        clk2 <= '0', '1' AFTER 10 ns, '0' AFTER 30 ns;
        WAIT FOR 35 ns;
   END PROCESS two_phase;
                               25
                   15
                         20
                                     30
                                           35
                                                 40
                                                                       60
              one period
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```

Assert Statement

- How do we check outputs?
- Assert statement is used to report information
- Assert statement checks a Boolean expression
 - if true, the statement does nothing
 - if false, the report string is output
- optional severity level to output string
 - note
 - warning
 - error
 - failure (will stop simulator)

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Test Bench Example

```
LIBRARY ieee;
USE ieee.std_logic_1164.ALL;

ENTITY test_bench IS

END test_bench;

ARCHITECTURE test_fixture OF test_bench IS

COMPONENT and_2

PORT (a, b : IN std_logic;

c : OUT std_logic);

END COMPONENT;

-- configuration statement - may be required by simulator

-- FOR ALL: and_2 USE ENTITY work.and2;

SIGNAL ina, inb, out1 : std_logic; -- local signal declarations
```

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Test Bench Example (cont'd)

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Test Bench Development

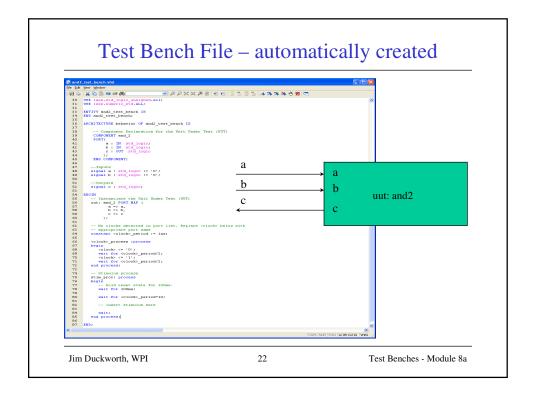
- Create synthesizable VHDL as usual
 - Will end up as hardware in FPGA
- Select Project => New Source = VHDL Test Bench
 - (do not use test bench waveform)
 - A skeleton for the test bench file opens with your component already declared and instantiated
 - Enter your test bench VHDL statements

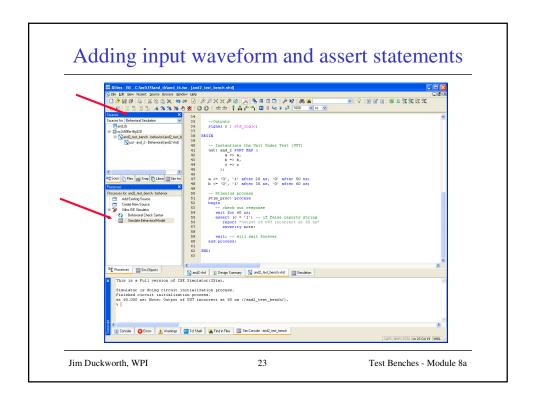


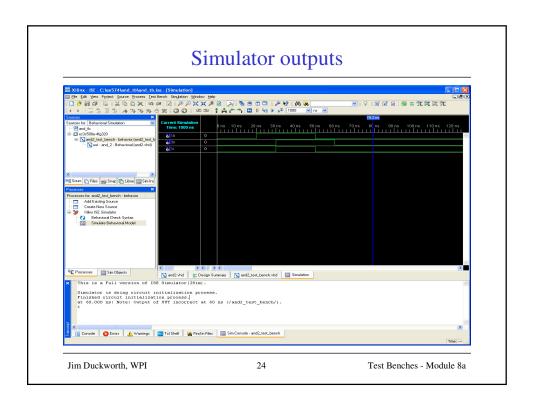
- Change from Implementation to Behavioral Simulation in the sources window
- Click on Simulate Behavioral VHDL Model
 - ISim or ModelSim starts and runs your test bench

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WAIT statements – provide timing control

- Three basic forms causes process to suspend
 - WAIT FOR time expression
 - WAIT FOR 20 ns;
 - WAIT UNTIL Boolean expression
 - WAIT UNTIL sum > 100;
 - WAIT ON sensitivity list
 - WAIT ON a, b, c; -- waits for an event to occur on signal a, b, or c
- Variations:
 - each time event on a signal occurs the expression is evaluated
 - WAIT UNTIL sum > 100 FOR 500 ns;
 - WAIT ON clk FOR 17 ms;

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Test Bench Example - shift register

- LS194 component (shift register) under test
- Start with synthesizable VHDL description

```
-- example of a 4-bit shift register
-- LS194 4-bit bidirectional universal shift register

LIBRARY ieee;
USE ieee.std_logic_1164.ALL;
ENTITY LS194 IS

PORT(clk, n_clr, s0, s1, sr_ser, s1_ser: IN std_logic;
abcd : IN std_logic_vector(3 DOWNTO 0);
q : OUT std_logic_vector(3 DOWNTO 0));
END LS194;
```

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LS194 Component (cont'd)

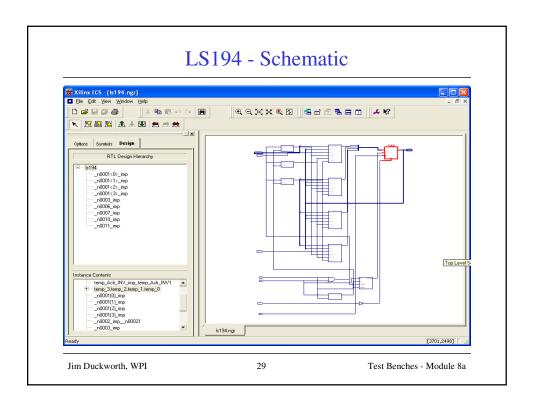
```
ARCHITECTURE behav OF LS194 IS
   SIGNAL temp : std_logic_vector(3 DOWNTO 0);
BEGIN
   PROCESS(clk, n_clr)
   BEGIN
        If n_clr = '0' THEN
                                   -- asynchronous clear
                temp <= "0000";
        ELSIF clk'EVENT AND clk = '1' THEN
                 IF s0 = '1' AND s1 = '1' THEN
                                                    -- synch load
                         temp <= abcd;
                 ELSIF s0 = '1' AND s1 = '0' THEN -- shift right
                         temp <= sr_ser & temp(3 DOWNTO 1);</pre>
                 ELSIF s0 = '0' AND s1 = '1' THEN -- shift left;
                         temp <= temp(2 DOWNTO 0) & sl_ser;</pre>
                                                    -- inhibit mode
                          temp <= temp;</pre>
                 END IF;
        END IF;
   END PROCESS;
   q <= temp;
END behav;
```

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LS194 — Synthesizable VHDL

| Compared to the property of the

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Test Bench for shift register

```
-- example of test_bench to test operation of '194 shift register
LIBRARY ieee;
USE ieee.std_logic_1164.ALL;
ENTITY test_bench IS
END test_bench;
ARCHITECTURE test_fixture OF test_bench IS
   COMPONENT 1s194
        PORT(clk, n_clr, s0, s1, sr_ser, sl_ser : IN std_logic;
               abcd : IN std_logic_vector(3 DOWNTO 0);
                        : OUT std_logic_vector(3 DOWNTO 0));
   END COMPONENT;
   FOR all: 1s194 USE ENTITY work.1s194; -- configuration
   -- define internal signals for connecting 1s194 to driver
   SIGNAL clk, s0, s1, n_clr, sr_ser, s1_ser : std_logic := '0';
                        : std_logic_vector(3 DOWNTO 0);
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```

Test Bench (cont'd)

```
BEGIN

-- instantiate ls194 shift register component shift_reg:
ls194 PORT MAP(clk, n_clr, s0, s1, sr_ser, sl_ser, abcd, q);

clk <= NOT clk AFTER 50 ns; -- create system clock

PROCESS
BEGIN

WAIT FOR 10 ns;
ASSERT q = "0000"
REPORT "ERROR: clear failed"
SEVERITY error;

WAIT FOR 20 ns;
n_clr <= '1';
```

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Test Bench (cont'd)

```
-- check synchronous load

s0 <= '1';
s1 <= '1';
abcd <= "0010";
WAIT UNTIL clk = '0'; -- first falling edge

ASSERT q = "0010"
REPORT "ERROR: load failed"
SEVERITY error;

-- now check shift left
s0 <= '0';
WAIT UNTIL clk = '0'; -- next falling clock edge

ASSERT q = "0011"
REPORT "ERROR: shift left failed"
SEVERITY error;
```

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Test Bench (cont'd)

```
FOR i IN 0 TO 2 LOOP -- three more shift lefts

IF i = 1 THEN

sl_ser <= '1';

ELSE

sl_ser <= '0';

END IF;

WAIT UNTIL clk = '0';

END LOOP;

ASSERT q = "1010"

REPORT "ERROR: serial shift left failed"

SEVERITY error;

WAIT; -- suspend

END PROCESS;
END test_fixture;
```

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Test Bench File

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Test Bench Simulation #**Error: ERROR: shift left failed # Time: 200 ns Iteration: 0 Instance /ls194_ls194_tb_vhd_tb #*Error: ERROR: serial shift left failed # Time: 500 ns Iteration: 0 Instance /ls194_ls194_tb_vhd_tb ### Time: 500 ns Iteration: 0 Instance /ls194_ls194_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_vhd_tb_

New Test Bench Design

```
-- creating a separate driver for the test bench
LIBRARY ieee;
USE ieee.std_logic_1164.ALL;
ENTITY 1s194_driver IS
        PORT(clk: BUFFER std_logic := '0'; -- notice buffer
        n_clr, s0, s1, sr_ser, sl_ser : OUT std_logic := '0';
        abcd : OUT std_logic_vector(3 DOWNTO 0);
               : IN std_logic_vector(3 DOWNTO 0));
END ls194_driver;
ARCHITECTURE behav OF ls194_driver IS
   clk <= NOT clk AFTER 50 ns; -- create system clock
   PROCESS
   BEGIN
        WAIT FOR 10 ns;
        ASSERT q = "0000"
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```

New Test Bench

